

# Investigation of localized electric fields of InAs/GaAs quantum dot interfaces

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In InAs/GaAs QDs, the strain-induced lattice deformation and strain induced dislocation could generate localized electric fields (LEF) due to the piezo-electric fields [1]. Therefore, the electric field distribution could be more complex at the interface of QDs than for the 2D superlattice (SL). The strain-induced complex electric fields can significantly modify the quantum confinement states. Direct observation of strain-related effects, such as the LEFs caused by strain-induced polarizations and defects, is therefore very important. Photorefectance spectroscopy (PR) is useful for investigating LEFs of semiconductors [2]. In the case of GaAs, the Franz-Keldysh oscillations (FKOs) that appear above the band gap of GaAs and contain information about the LEFs in GaAs. To investigate InAs/GaAs quantum confinement states, PR experimental results were reported [3]. However, experimental observation of LEFs attributed to strain between InAs QD and GaAs has not been the focus of many studies.

In this work, we investigated LEFs between InAs QD and GaAs by PR. FIG.1 shows the InAs/GaAs QDs sample used in this work. FIG. 2 shows the PR spectra of the InAs/GaAs QD samples obtained at low temperature. The low-temperature PR spectrum of the InAs/GaAs QD shows clear FKO transitions above the GaAs band gap energy. This work suggests that the interface electric fields attributed to strain originate from the strain-induced polarization near the InAs QD interface in GaAs. We suggested that the FKOs originated from the LEFs predominately caused by the strain-induced polarization at the GaAs interface near the InAs QDs. The InAs/GaAs QDs have a broad range of interface electric fields from  $\sim 10^4$  V/cm to  $\sim 2 \times 10^5$  V/cm.

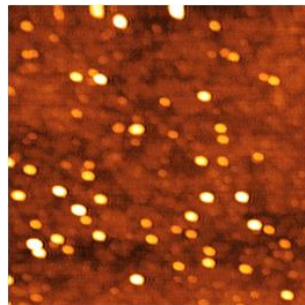


Figure 1. AFM image of InAs/GaAs QD

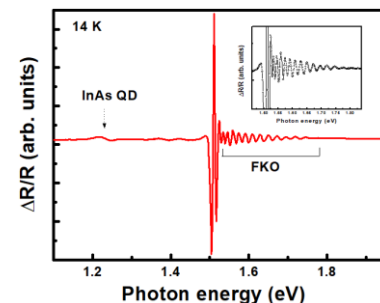


Figure 2. Low temperature PR spectrum of InAs/GaAs QD

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